ABSTRACT OF THE DISCLOSURE

A method of discriminating between different types of simulated scan failures includes simulating a scan enable signal to a circuit represented by a netlist corresponding to a scan chain coupled to combinatorial logic being tested, simulating initiation of a data capture cycle in the netlist corresponding to the scan chain, the data capture cycle simulating a series of scan flops from the scan chain being simulated together with the combinatorial logic and simulating scanning data out from each flop in the scan chain and into a test program. The test program extracts the simulated scan flops and graphically displays the simulated scan flops versus time.